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**INFORMATION DISCLOSURE  
STATEMENT BY APPLICANT**

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Shee

Complete if Known

Application Number	10/601,802
Filing Date	23 June 2003
First Named Inventor	Joseph C. Marron
Group Art Unit	unknown
Examiner Name	
Attorney Docket Number	Marron 06/03-2

**U.S. PATENT DOCUMENTS**

## FOREIGN PATENT DOCUMENTS

Examiner  
Signature

S.A. Tunca

**Date Considered**

12-8-03

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Application Number	10601,802
Filing Date	23 June 2003
First Named Inventor	Joseph C. Marron
Group Art Unit	unknown
Examiner Name	Unknown
Attorney Docket Number	Marron 06/03-2

OTHER PRIOR ART – NON PATENT LITERATURE DOCUMENTS		
Examiner Initials*	Cite No.*	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city, and/or country where published.
SAT		"Multiple-wavelength Interferometry With Tunable Source", R.G. Pilston and G.N. Steinberg, Applied Optics, Vol. 8, No. 3, March 1969, pp. 552-556
	↑	"Two-wavelength Interferometry", D. Malarcara, editor, Optical Shop Testing, New York, Wiley, 1978, pp. 397-402
		"Multiple-wavelength Phase-shifting Interferometry", Y. Cheng and J.C. Wyant, Applied Optics, Vol. 24, No. 6, 15 March 1985, pp. 804-806
		"Distance measurement by the wavelength shift of laser diode light", H. Kikuta, K. Iwata, and R. Nagata, Applied Optics, Vol. 25, No. 17, 1 September 1986, pp. 2976-2980
		"Interferometer for measuring displacement and distance", T. Kubota, M. Nara, and T. Yoshino, Optics Letters, Vol. 12, No. 5, May 1987, pp. 310-312
		"Three-color laser-diode interferometer", P. de Groot, Applied Optics, Vol. 30, No. 25, 1 September 1991, pp. 3612-3616
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	↑	"Three-dimensional lensless imaging using laser frequency diversity", J.C. Marron and K.S. Schroeder, Applied Optics, Vol. 31, No. 2, 10 January 1992, pp. 255-262
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	↓	"Use of a opacity constraint in three-dimensional imaging", R.G. Paxman, J.H. Seldin, J.R. Fienup, and J.C. Marron, in proceedings of the SPIE Conference on Inverse Optics III, Orlando, Florida, April 1994
SAT		"Applications of Tunable Lasers to Laser Radar and 3D Imaging", L.G. Shirley and G.R. Hallerman, Technical Report 1025, Lincoln Laboratory, MIT, Lexington, Massachusetts, 26 February 1996

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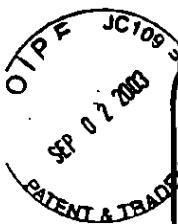
\*Unique citation designation number. <sup>2</sup> Applicant is to place a check mark here if English language Translation is attached.

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SJT		"Wavelength scanning profilometry for real-time surface shape measurement", S. Kuwamura and I. Yamaguchi, Applied Optics. Vol. 36, No. 19, 1 July 1997, pp. 4473-4482	
	↑	"Three-dimensional imaging using a tunable laser source", J.C. Marron and K.W. Gleichman, Optical Engineering 39(1) 47-51, January 2000, pp. 47-51	
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		"Novel geometry for single-mode scanning of tunable lasers", K. Liu and M.G. Littman, Optics Letters, Vol. 6, No. 3, March 1981, pp. 117-118	
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		"Littrow configuration tunable external cavity diode laser with fixed direction output beam", C.J. Hawthorn, K.P. Weber and R.E. Scholten, Review of Scientific Instruments, Vol. 72, No. 12, December 2001, pp. 4477-4479	
		"Fizeau Interferometer", D. Malarcara, editor, Optical Shop Testing, New York, Wiley, 1978, pp.19-24	
SJT	↓	"Burch's Interferometer Employing Two Matched Scatter Plates", D. Malarcara, editor, Optical Shop Testing, New York, Wiley, 1978, pp. 82-84	

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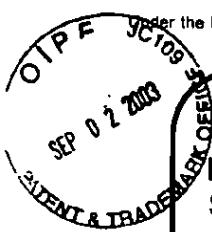
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S.A. T.		"Holographic contouring by using tunable lasers", N. George and W. Li, Optics Letters, Vol. 19, No. 22, 15 November 1994, pp. 1879-1881
		"Use of a multimode short-external-cavity laser diode for absolute-distance interferometry", P. de Groot, Applied Optics, Vol. 32, No. 22, 1 August 1993, pp. 4193-4198
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		Littrow-Laser web site sacher.de/littrow.htm, 07 April 2002
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		"Scatter Fringes of Equal Thickness", J.M. Burch, Nature, Vol. 17, May 16, 1953, pp. 889-890.
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		"Laser Speckle and Related Phenomena", J.C. Dainty, editor, Springer-Verlag, Berlin, 1984.
S.A.T.		"Digital Picture Processing", A. Rosenfeld, and A.C. Kak, Vol. 1., Academic Press, New York, 1982.

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